

Explorations in low area overhead DfT techniques for sequential BIST

Raik, Jaan; Raidma, Rein; **Ubar, Raimund-Johannes** IEEE NORCHIP 2003 : 21 Norchip Conference : Riga, Latvia, 10-11 November 2003 : proceedings 2003 / p. 220-223 : ill

Fast test cost calculation for hybrid BIST in digital systems

Orasson, Elmet; Raidma, Rein; **Ubar, Raimund-Johannes**; **Jervan, Gert**; Peng, Zebo Euromicro Symposium on Digital Systems Design : [Architectures, Methods and Tools : DSD 2001] : September 4-6, 2001, Warsaw, Poland : proceedings 2001 / p. 318-325 : ill

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